Hybrid 8j6 Traveler

December 20, 1999

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J6 has die: 065-026 065-030 065-031 065-036 060-034 060-035 060-036 060-037

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j6 classification info. Created 17:39:37 12/10/99

Hybrid 8j6 quality: fair
Chip classification: good fair fair good good fair good good
Bad channels (chip-channel): 1-9 5-21 5-22
Bad cells: none
Random bad capacitors (chip-cell-channel): 2-0-4 2-0-5 2-1-5
   2-13-5 2-2-5 2-27-4 2-27-5 2-30-4 2-30-5 2-31-5 2-33-4
   2-33-5 2-35-4 2-35-5 2-37-4 2-37-5
Channels at pedestal needed for DCMS: 35.6 36.6 35.7 36.7 36.5 35.5 36.6 36.6
```

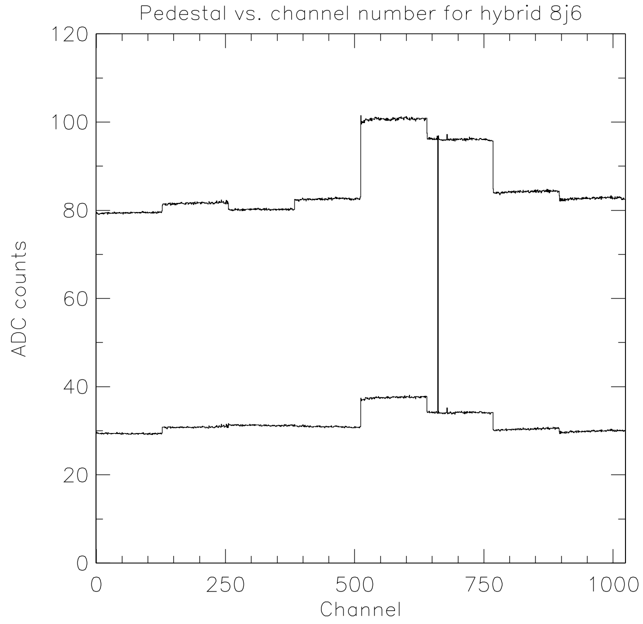
4 Comments

No comments.

5 Pedestal

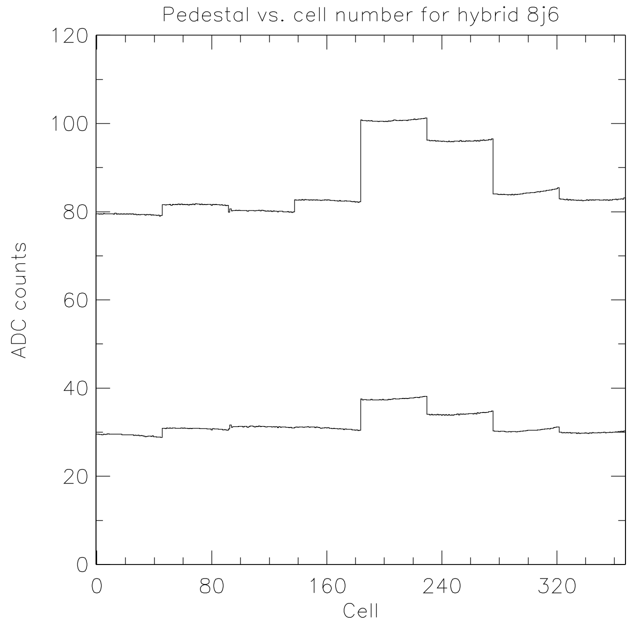
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

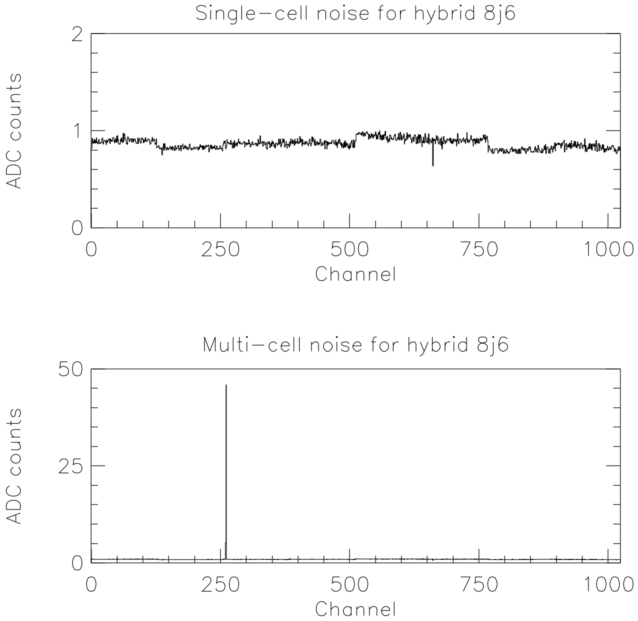
Pedestal vs. Pipeline Cell ID



6 Noise

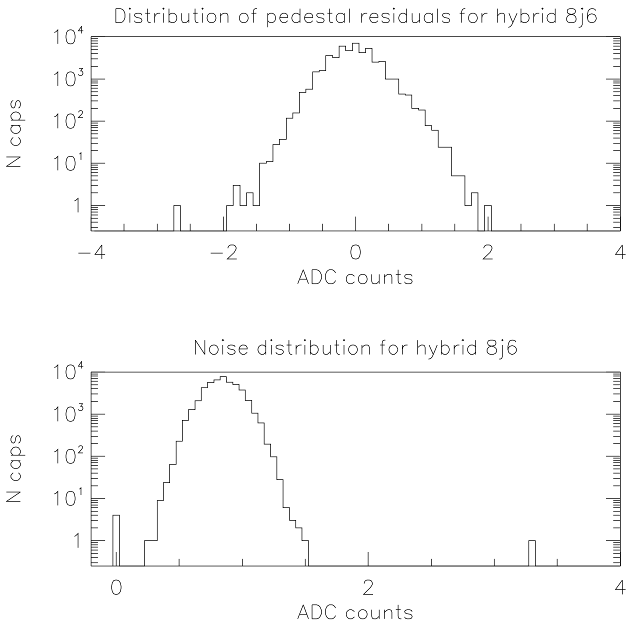
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise



The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in